

AN-306 APPLICATION NOTE

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## Synchronous System Measures $\mu\Omega s$

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The circuit in Fig 1 uses a synchronous-detection scheme to measure low-level resistances. Other lowresistance-measuring circuits sometimes inject unacceptably large currents into the system under test. This circuit synchronously demodulates the voltage drop across the system under test and can hence use extremely low currents while measuring resistance.

The 10V-pk, 1-kHz carrier generator injects a 1-mA reference current into unknown resistor,  $R_{TEST}$ . Instrument amplifier IC<sub>1</sub> and precision op amp IC<sub>2A</sub> amplify the voltage across  $R_{TEST}$  by a gain of 100,000. Synchronous detector IC<sub>3</sub> demodulates this voltage, then op

amp  $IC_{2B}$  acts as a lowpass filter on the demodulated voltage. The lowpass filtering will attenuate all uncorrelated disturbances, such as noise, drift, or offsets, while passing a dc voltage proportional to the unknown resistance.

The relationship between the output voltage and the unknown resistance is

$$V_{OUT} = 10 \times (2V/\pi) \times R_{TEST} \times 10^5/10 \text{ k}\Omega$$
, or  
R = 0.0157 × V<sub>OUT</sub>,

which is 15.7 m $\Omega$ /V at the circuit's output.



Fig 1—A synchronous demodulator helps this circuit measure low-level resistances while rejecting uncorrelated disturbances, such as noise, drift, and offsets.